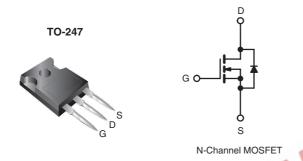


Vishay Siliconix

Power MOSFET

PRODUCT SUMMARY				
V _{DS} (V)	500			
$R_{DS(on)}\left(\Omega\right)$	V _{GS} = 10 V	0.60		
Q _g (Max.) (nC)	84			
Q _{gs} (nC)	8.4			
Q _{gd} (nC)	50			
Configuration	Single			



FEATURES

- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- Isolated Central Mounting Hole
- · Fast Switching
- · Ease of Paralleling
- Simple Drive Requirements
- Lead (Pb)-free Available

DESCRIPTION

Third Generation Power MOSFETs from Vishay provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance cost-effectiveness.

The TO-247 package is preferred for commercial-industrial applications where higher power levels preclude the use of TO-220 devices. The TO-247 is similar but superior to the earlier TO-218 package because of its isolated mounting hole. It also provides greater creepage distance between pins to meet the requirements of most safety specifications.

ORDERING INFORM	IATION	7	
Package			TO-247
Lead (Pb)-free			IRFP448PbF
			SiHFP448-E3
SnPb			IRFP448
			SiHFP448

ABSOLUTE MAXIMUM RATINGS T	_C = 25 °C, u	nless otherw	ise noted			
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V_{DS}	500	V	
Gate-Source Voltage			V_{GS}	± 20	1 v	
Continuous Drain Current	V _{GS} at 10 V	T _C = 25 °C	I-	11		
	VGS at 10 V	T _C = 100 °C	ID	6.6	Α	
Pulsed Drain Current ^a			I _{DM}	44		
Linear Derating Factor				1.4	W/°C	
Single Pulse Avalanche Energy ^b			E _{AS}	550	mJ	
Repetitive Avalanche Current ^a			I _{AR}	11	Α	
Repetitive Avalanche Energy ^a			E _{AR}	18	mJ	
Maximum Power Dissipation	T _C =	25 °C	P_D	180	W	
Peak Diode Recovery dV/dt ^c			dV/dt	3.5	V/ns	
Operating Junction and Storage Temperature Range			T _J , T _{stg}	- 55 to + 150	°C	
Soldering Recommendations (Peak Temperature)	for	10 s	-	300 ^d		
Mounting Torque	6 20 or l	6-32 or M3 screw		10	lbf ⋅ in	
	0-32 OF IVIS SCIEW			1.1	N · m	

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. $V_{DD}=50$ V, starting $T_J=25$ °C, L = 8.2 mH, $R_G=25$ Ω , $I_{AS}=11$ A (see fig. 12). c. $I_{SD}\leq 11$ A, $dI/dt\leq 120$ A/ μ s, $V_{DD}\leq V_{DS}$, $T_J\leq 150$ °C.

- d. 1.6 mm from case.

^{*} Pb containing terminations are not RoHS compliant, exemptions may apply

IRFP448, SiHFP448

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THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient	R _{thJA}	-	40		
Case-to-Sink, Flat, Greased Surface	R _{thCS}	0.24	-	°C/W	
Maximum Junction-to-Case (Drain)	R_{thJC}	-	0.70		

PARAMETER	SYMBOL	TEST	MIN.	TYP.	MAX.	UNIT	
Static				L			
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		500	-	-	٧
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference t	-	0.60	-	V/°C	
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V$	V _{DS} = V _{GS} , I _D = 250 μA		-	4.0	٧
Gate-Source Leakage	I _{GSS}	V _G	_S = ± 20 V	-	-	± 100	nA
Zero Gate Voltage Drain Current	I _{DSS}		V _{DS} = 500 V, V _{GS} = 0 V V _{DS} = 400 V, V _{GS} = 0 V, T _J = 125 °C			25 250	μΑ
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	$I_D = 9.0 \text{ A}^b$	_	-	0.60	Ω
Forward Transconductance	9 _{fs}	$V_{DS} = 50 \text{ V}, I_{D} = 6.6 \text{ A}^{b}$		6.7	-	-	S
Dynamic		132	-011	I.			
Input Capacitance	C _{iss}	$V_{GS} = 0 \text{ V},$ $V_{DS} = 25 \text{ V},$ f = 1.0 MHz, see fig. 5		-	1900	-	pF
Output Capacitance	C _{oss}			-	490	-	
Reverse Transfer Capacitance	C _{rss}			-	220	-	
Total Gate Charge	Qg			-	-	84	
Gate-Source Charge	Q _{gs}	$V_{GS} = 10 \text{ V}$ $I_D = 9.6 \text{ A}, V_{DS} = 400 \text{ V},$ see fig. 6 and 13 ^b		-	-	8.4	nC
Gate-Drain Charge	Q _{gd}			-	-	50	
Turn-On Delay Time	t _{d(on)}	$V_{DD}=250~\text{V, I}_D=9.6~\text{A}~,$ $R_G=7.8~\Omega,~R_D=27~\Omega,~\text{see fig. }10^\text{b}$		-	18	-	- ns
Rise Time	t _r			-	40	-	
Turn-Off Delay Time	t _{d(off)}			-	62	-	
Fall Time	t _f		-	32	-		
Internal Drain Inductance	L _D		Between lead, 6 mm (0.25") from			-	
Internal Source Inductance	L _S	package and center of die contact		-	13	-	- nH
Drain-Source Body Diode Characteristic	s	1				•	
Continuous Source-Drain Diode Current	Is	MOSFET symbol showing the integral reverse p - n junction diode		-	-	11	
Pulsed Diode Forward Current ^a	I _{SM}			-	-	44	A
Body Diode Voltage	V_{SD}	T _J = 25 °C, I _S = 11 A, V _{GS} = 0 V ^b		-	-	1.7	V
Body Diode Reverse Recovery Time	t _{rr}	$T_J = 25 ^{\circ}\text{C}, \ I_F = 9.6 \text{A}, \ \text{dI/dt} = 100 \text{A/}\mu\text{s}^{\text{b}}$		-	480	1100	ns
Body Diode Reverse Recovery Charge	Q _{rr}			-	5.2	12	μC
Forward Turn-On Time	t _{on}	Intrinsic turn	on is dor	ninated b	y L _S and	L _D)	

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Pulse width $\leq 300~\mu s;$ duty cycle $\leq 2~\%.$





TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

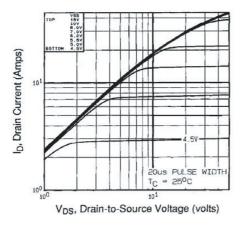


Fig. 1 - Typical Output Characteristics, T_C = 25 °C

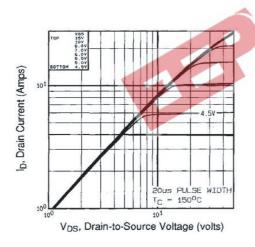
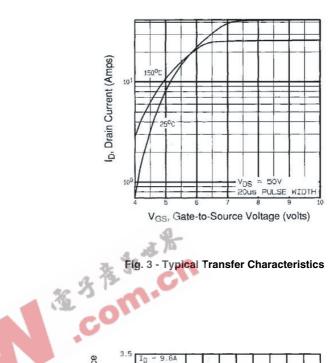


Fig. 2 - Typical Output Characteristics, T_C = 150 °C



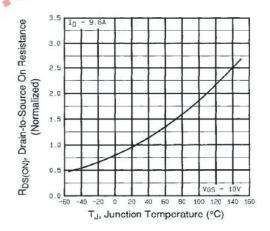


Fig. 4 - Normalized On-Resistance vs. Temperature

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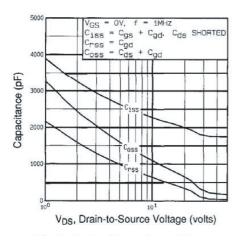
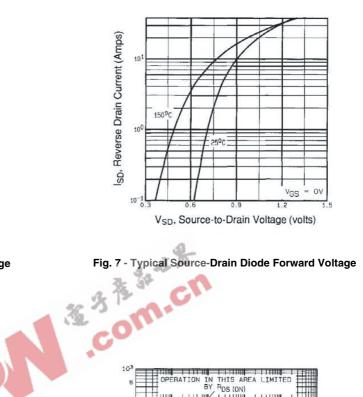


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage



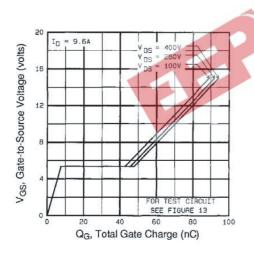


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

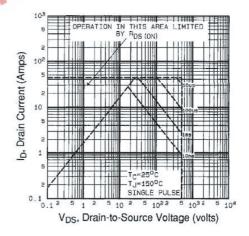
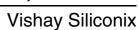


Fig. 8 - Maximum Safe Operating Area





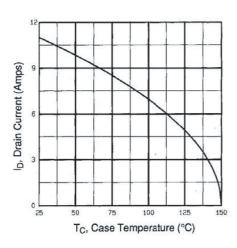


Fig. 9 - Maximum Drain Current vs. Case Temperature

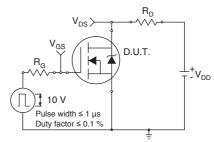


Fig. 10a - Switching Time Test Circuit

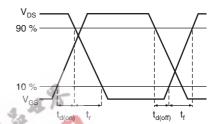


Fig. 10b - Switching Time Waveforms

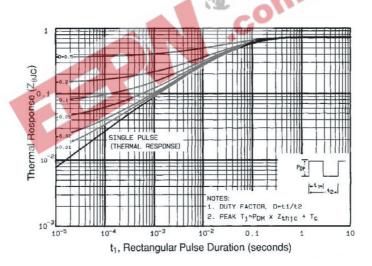
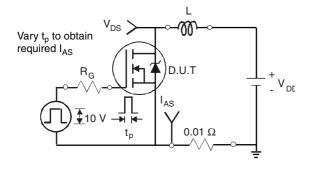


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

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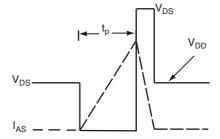


Fig. 12a - Unclamped Inductive Test Circuit

Fig. 12b - Unclamped Inductive Waveforms

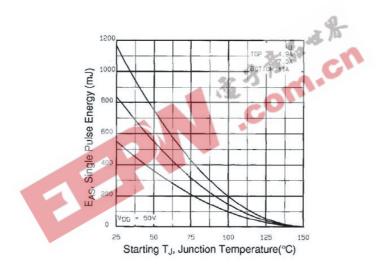


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

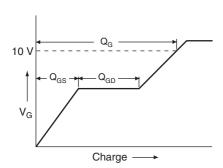


Fig. 13a - Basic Gate Charge Waveform

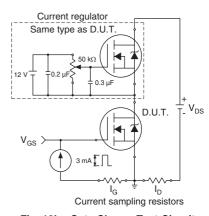
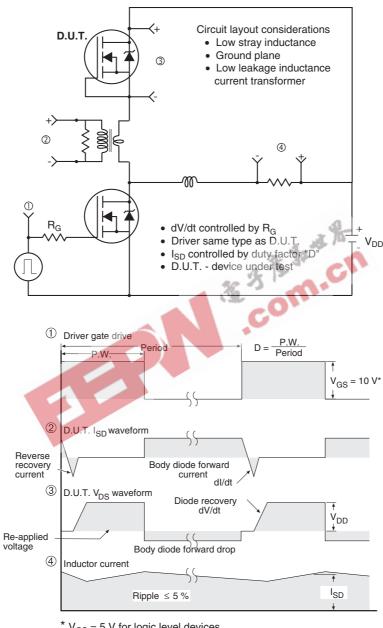


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit



* $V_{GS} = 5 V$ for logic level devices

Fig.14 - For N-Channel

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